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Ali M. Khounsary
Gert E. van Dorssen
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Contents

v *Authors*
vii *Conference Committee*

SESSION 1 NOVEL LABORATORY X-RAY SOURCES I

- 9964 02 **A compact, coherent light source system architecture** [9964-2]
9964 04 **Advanced controls for light sources** [9964-4]

SESSION 2 NOVEL LABORATORY X-RAY SOURCES II

- 9964 05 **Image-based characterization of microfocus x-ray target failure** [9964-5]
9964 06 **Simulations of laser undulators** [9964-6]
9964 08 **A case for ZnO nanowire field emitter arrays in advanced x-ray source applications**
[9964-8]

SESSION 3 LABORATORY-BASED X-RAY OPTICS

- 9964 09 **Development of polycapillary x-ray optics for x-ray spectroscopy** [9964-9]
9964 0A **Large field-of-view asymmetric masks for high-energy x-ray phase imaging with standard x-ray tube** [9964-10]

SESSION 4 LABORATORY-BASED X-RAY APPLICATIONS

- 9964 0E **Simulation tools for analyzer-based x-ray phase contrast imaging system with a conventional x-ray source** [9964-13]
9964 0F **X-ray phase scanning setup for non-destructive testing using Talbot-Lau interferometer**
[9964-14]
9964 0G **High-resolution radiography of thick steel objects using an all-laser-driven MeV-energy x-ray source** [9964-15]
9964 0I **Laboratory-based x-ray phase-contrast tomography enables 3D virtual histology** [9964-19]

POSTER SESSION

9964 0J **Laboratory and synchrotron tests of two-dimensional parabolic x-ray compound refractive lens made of single-crystal diamond [9964-17]**

Authors

Numbers in the index correspond to the last two digits of the six-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first four digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Adams, Bernhard W., 09
Astolfo, A., 0A
Attenkofer, Klaus, 09
Bachche, S., 0F
Banerjee, Sudeep, 0G
Barannikov, A., 0J
Bergkvist, Magnus, 08
Biedron, S. G., 02, 04, 06
Blank, V. D., 0J
Bond, Justin L., 09
Brankov, J. G., 0E
Caudevilla, Oriol, 0E
Chen, Daokun, 08
Chen, Jun, 08
Chen, Shouyuan, 0G
Craven, Christopher A., 09
Cremer, Till, 09
Dattoli, G., 02
Denisov, V. N., 0J
DiPalma, E., 02
Edelen, A. L., 04
Einstein, J. E., 02, 06
Endrizzi, M., 0A
Fruhling, Colton, 0G
Golovin, Grigory, 0G
Haden, Daniel, 0G
Haig, I., 0A
Huang, Mengbing, 08
Kageyama, M., 0F
Kato, K., 0F
Koike, T., 0F
Kornilov, N. V., 0J
Krenkel, Martin, 0I
Kuribayashi, M., 0F
Martyushov, S. Yu., 0J
Milton, S. V., 02, 04, 06
Minot, Michael J., 09
Momose, A., 0F
Nonoguchi, M., 0F
Olivo, A., 0A
O'Mahony, Aileen, 09
Petrillo, V., 02
Polikarpov, M., 0J
Polyakov, S. N., 0J
Popecki, Mark A., 09
Price, B., 0A
Quade, Felix, 0I
Raber, Thomas, 05
Rau, J. V., 02
Robinson, Vance S., 05, 08
Ross, William R., 05
Sabia, E., 02
Salditt, Tim, 0I
Snigirev, A., 0J
Snigireva, I., 0J
Spassovsky, I. P., 02
Stoupin, Stanislav, 0E
Terentiev, S. A., 0J
Töpperwien, Mareike, 0I
Umstadter, Donald, 0G
van der Slot, P. J. M., 02
Verman, Boris, 0E
Yan, Wenchao, 0G
Zhang, Ping, 0G
Zhao, Baozhen, 0G
Zholudev, S. I., 0J
Zhou, Wei, 0E
Zverev, D., 0J

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